



## Dual P-Channel 1.8-V (G-S) MOSFET

### CHARACTERISTICS

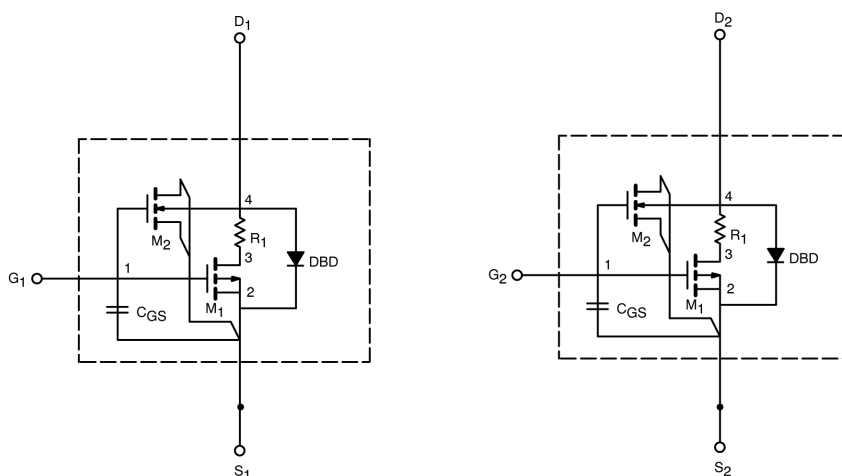
- P-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the  $-55$  to  $125^{\circ}\text{C}$  Temperature Range
- Model the Gate Charge, Transient, and Diode Reverse Recovery Characteristics

### DESCRIPTION

The attached spice model describes the typical electrical characteristics of the p-channel vertical DMOS. The subcircuit model schematic is extracted and optimized over the  $-55$  to  $125^{\circ}\text{C}$  temperature ranges under the pulsed 0-to-5V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched  $C_{gd}$  model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device(s).

### SUBCIRCUIT MODEL SCHEMATIC



This document is intended as a SPICE modeling guideline and does not constitute a commercial product data sheet. Designers should refer to the appropriate data sheet of the same number for guaranteed specification limits.

# SPICE Device Model Si6969DQ

Vishay Siliconix



| SPECIFICATIONS (T <sub>J</sub> = 25°C UNLESS OTHERWISE NOTED) |                     |                                                                                                            |         |      |
|---------------------------------------------------------------|---------------------|------------------------------------------------------------------------------------------------------------|---------|------|
| Parameter                                                     | Symbol              | Test Conditions                                                                                            | Typical | Unit |
| <b>Static</b>                                                 |                     |                                                                                                            |         |      |
| Gate Threshold Voltage                                        | V <sub>GS(th)</sub> | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA                                               | 0.83    | V    |
| On-State Drain Current <sup>a</sup>                           | I <sub>D(on)</sub>  | V <sub>DS</sub> = -V, V <sub>GS</sub> = -V                                                                 |         | A    |
| Drain-Source On-State Resistance <sup>a</sup>                 | r <sub>DS(on)</sub> | V <sub>GS</sub> = -V, I <sub>D</sub> = -A                                                                  |         | Ω    |
|                                                               |                     | V <sub>GS</sub> = -V, I <sub>D</sub> = -A                                                                  |         |      |
|                                                               |                     | V <sub>GS</sub> = -V, I <sub>D</sub> = -A                                                                  |         |      |
| Forward Transconductance <sup>a</sup>                         | g <sub>fs</sub>     | V <sub>DS</sub> = -V, I <sub>D</sub> = -A                                                                  |         | S    |
| Diode Forward Voltage <sup>a</sup>                            | V <sub>SD</sub>     | I <sub>S</sub> = -A, V <sub>GS</sub> = 0 V                                                                 |         | V    |
| <b>Dynamic<sup>b</sup></b>                                    |                     |                                                                                                            |         |      |
| Total Gate Charge                                             | Q <sub>g</sub>      | V <sub>DS</sub> = -V, V <sub>GS</sub> = -V, I <sub>D</sub> = -A                                            |         | nC   |
| Gate-Source Charge                                            | Q <sub>gs</sub>     |                                                                                                            |         |      |
| Gate-Drain Charge                                             | Q <sub>gd</sub>     |                                                                                                            |         |      |
| Turn-On Delay Time                                            | t <sub>d(on)</sub>  | V <sub>DD</sub> = -V, R <sub>L</sub> = Ω<br>I <sub>D</sub> = -A, V <sub>GEN</sub> = -V, R <sub>G</sub> = Ω |         | ns   |
| Rise Time                                                     | t <sub>r</sub>      |                                                                                                            |         |      |
| Turn-Off Delay Time                                           | t <sub>d(off)</sub> |                                                                                                            |         |      |
| Fall Time                                                     | t <sub>f</sub>      |                                                                                                            |         |      |
| Source-Drain Reverse Recovery Time                            | t <sub>rr</sub>     | I <sub>F</sub> = -A, di/dt = 100 A/μs                                                                      |         |      |

## Notes

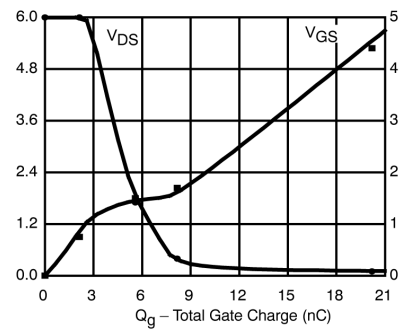
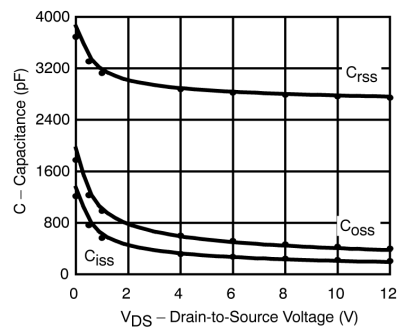
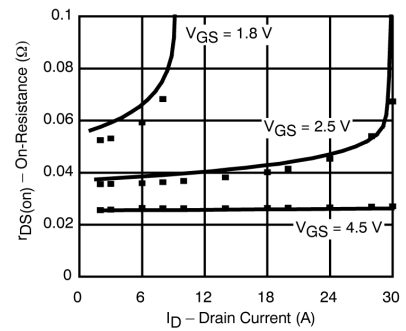
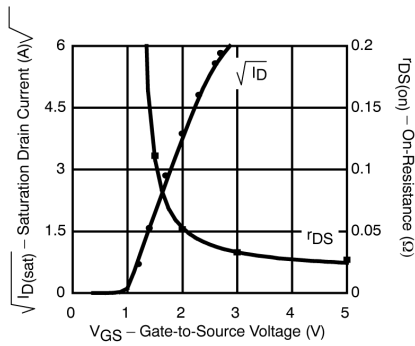
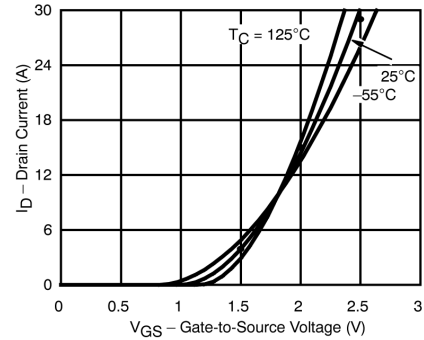
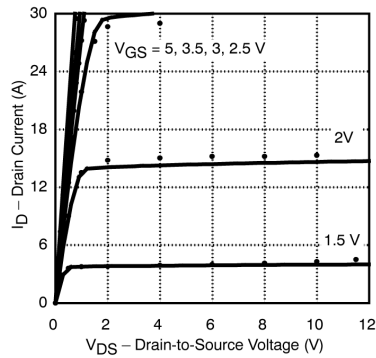
- a. Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2%.  
b. Guaranteed by design, not subject to production testing.



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COMPARISON OF MODEL WITH MEASURED DATA ( $T_J=25^\circ\text{C}$  UNLESS OTHERWISE NOTED)



Note: Dots and squares represent measured data.